


<b>Search Notes</b>  	<b>Application/Control No.</b>  10561200	<b>Applicant(s)/Patent Under Reexamination</b>  AIHARA ET AL.
	<b>Examiner</b>  /Mark L Berch/	<b>Art Unit</b>  1624

SEARCHED			
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SEARCH NOTES		
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540/200 plus text terms	10/7/2008	mlb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
540	200	10/7/2008	mlb

	//Mark L Berch// Primary Examiner.Art Unit 1624
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